LATW2004

5thIEEELatin-AmericanTestWorkshop

Cartagena, Colombia

March 8-10, 2004

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The IEEE Latin-American Test Workshop provides an annual forum for test and fault tolerance professionals and technologists from Latin American and all over the world to present and discuss various aspects of system, board and component testing and fault-tolerance with design, manufacturing and field considerations in mind. For this 5th edition, LATW will be held in conjunction with the X Workshop IBERCHIP, which will be realized from March 10th at the same place. The best papers presented at the 5th LATW will be invited to be re-submitted for a Special Issue of the Journal of Electronics Testing: Theory and Applications (JETTA), published by Kluwer Academic Publishers.

Topics of interest include but are not limited to:

- Analog Mixed Signal Test
- Automatic Test Generation
- Built-In Self-Test
- Defect-Based Test
- Dependability Estimation
- Design and Synthesis for Testability
- Design Verification/Validation
- E-Beam and Thermal Testing
- Economics of Test
- Fault Analysis and Diagnosis
- Fault Modeling and Simulation
- Fault-Tolerance in HW/SW
- Fault-Tolerant Architectures
- Memory Test and Repair
- On-Line Testing
- Process Control and Measurements
- Radiation Hardening Techniques
- System-on-Chip Test
- Test Resource Partitioning
- Yield Optimization

Paper Submission Information:

To encourage and facilitate informal discussion, participation will be limited. Those interested in presenting recent results at the workshop are invited to submit either an extended abstract, one to three pages long, or a full length paper.Post-Script or PDF electronic submissions **via the workshop web page are strongly recommended.**

www.latw.net

Authors should send papers in the IEEE format with a cover letter indicating the complete mail address, phone/fax numbers and e-mail addresses, the contact person and the presenter. Detailed instructions are available at the workshop web page. The Program Committee also welcomes proposals for panels and special topic sessions. For additional information please contact one of the Program Chairs.

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Submission deadline: November 10th, 2003
Notification of acceptance: December 12th, 2003
Camera Ready: January 12th, 2004

LATW2004 will be held in Cartagena, Colombia. Cartagena de Indias is one of the most beautiful colonial cities in Latin America, where you will be surprised at every step by an incredible history filled with magic and charm as the historical Old City or in the nearby Islas del Rosario, just 40 minutes by boat. It could be said that this is the city with the most titles on the continent: "Diplomatic City" "Historical Heritage of Mankind" (given by UNESCO in 1985), "Best Fortified City of America" "Walled Kingdom" "Key to the West Indies," and "Heroic City" a name given by Simón Bolívar, the Liberator. Cartagena is just two hours from Miami and 45 minutes from Bogota.

Sponsored by:

IEEE Computer Society Test Technology Technical Council (TTTC)

In Cooperation with:

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